**What Is Claimed Is:**

1.  A    system    for    WAT    (Wafer    Acceptance    Test)
configuration, comprising:

an input/output device receiving a first WAT model and

5           qualification criteria;

a   storage   device   storing   a   preset   WAT   model   and

qualification criteria; and

a processor modifying the preset WAT model according to the

first WAT model to generate a second WAT model, and

10          modifying    the    preset    qualification    criteria

according  to  the  first  qualification  criteria  to

generate qualification criteria.

2.    The  system  of  claim  1,  further  comprising  a  WAT
control mechanism transforming the second WAT model into a test

15  program operable on a selected target WAT platform.

3.    The system of claim 1, further comprising a quality
control mechanism performing a quality examination according to
the second qualification criteria.

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4.    The system of claim 1, further comprising an engineering support mechanism generating a report according to the second qualification criteria, WAT results, and quality examination results.

5        5.    The system of claim 1, wherein the WAT model specifies number and arrangement of test sites in a WAT.

6.    The system of claim 1, wherein the qualification criteria specifies a key parameter.

7.    The system of claim 1, wherein the qualification criteria specifies an acceptable quality level.

8.    A    method    for    WAT    (Wafer    Acceptance    Test) configuration, comprising:

providing a preset WAT model and qualification criteria;

providing a first WAT model and qualification criteria;

15        modifying the preset WAT model according to the first WAT

model to generate a second WAT model;

modifying the preset qualification criteria according to

the first qualification criteria to generate second

qualification criteria.

9.   The   method   of   claim   8,   further   comprising
transforming the second WAT model into a test program operable
on a selected target WAT platform.

10.   A method of claim 8, further comprising performing a
quality examination based on the second qualification criteria.

11.   The method of claim 8, further comprising generating
a quality report according to results of the WAT and the quality
examination.

12.   The method of claim 8, wherein the WAT model specifies
number and arrangement of test sites in WAT.

13.   The   method   of   claim   8,   wherein   the   qualification
criteria specifies a key parameter.

14.   The   method   of   claim   8,   wherein   the   qualification
criteria specifies an acceptable quality level.

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15.  A computer readable storage medium storing a computer program providing a method for WAT (Wafer Acceptance Test) configuration, comprising:

receiving preset test and qualification criteria;

5        receiving first test and qualification criteria;

modifying the preset WAT model according to the first WAT model to generate a second WAT model;

modifying the preset qualification criteria according to the first qualification criteria to generate second

10        qualification criteria.

16.  The storage medium of Claim 15, wherein the method further comprises transforming the second WAT model into a test program operable on a selected target WAT platform.

17.  The storage medium of Claim 15, wherein the method

15  further comprises performing a quality examination based on the second qualification criteria.

18.    The storage medium of Claim 15, wherein the method

further comprises generating a quality report according to

results of the WAT and the quality examination.

19.    The storage medium of Claim 15, wherein the WAT model

5    specifies the number and arrangement of test sites in a WAT.

20.    The    storage    medium    of    Claim    15,    wherein    the

qualification criteria specifies a key parameter.

21.    The    storage    medium    of    Claim    15,    wherein    the

qualification criteria specifies an acceptable quality level.

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